



<b>SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT BY APPLICANT PTO-1449</b>	Docket No. <b>52433/820</b>	Application No. <b>10/551,159</b>
	Applicant(s) <b>TANAKA et al.</b>	Examiner <b>Michael E. LAVILLA</b>
	Filing Date <b>September 28, 2005</b>	Confirmation No. <b>3164</b>
		Art Unit <b>1775</b>

**U. S. PATENT DOCUMENTS**

EXAMINER INITIAL	PATENT/PUBLICATION NUMBER	PATENT/PUBLICATION DATE mm/dd/yyyy	NAME	CLASS	SUBCLASS	FILING DATE
/ML/	2001/0031377	October 18, 2001	Hashimoto et al.			
/ML/	2002/0160221	October 31, 2002	Takeda et al.			
/ML/	2003/0054195	March 20, 2003	Ishii et al.			

**FOREIGN PATENT DOCUMENTS**

EXAMINER INITIAL	DOCUMENT NUMBER	DATE mm/dd/yyyy	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						Yes	No
/ML/	EP 1 076 105 A1	February 14, 2001	EP				
/ML/	EP 1 149 928 A1	October 31, 2001	EP				
/ML/	JP 2001-279412	October 10, 2001	JP			Abstract	

**OTHER DOCUMENTS**

EXAMINER INITIAL	AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.
/ML/	Supplementary European Search Report of European Patent Application No. EP 04 72 4397 mailed November 22, 2007

EXAMINER	DATE CONSIDERED
/Michael LaVilla/	06/01/2008
EXAMINER: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	